



# THE DATASHEET OF FQB3P20TM





April 2000

**QFET™**

## FQB3P20 / FQI3P20

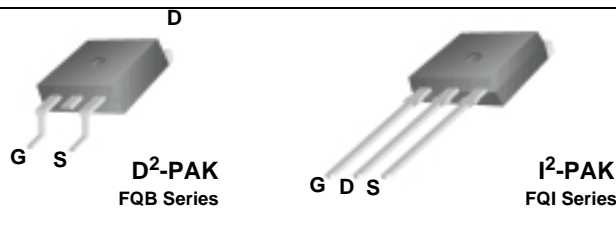
### 200V P-Channel MOSFET

#### General Description

These P-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switching DC/DC converters.

#### Features

- -2.8A, -200V,  $R_{DS(on)} = 2.7\Omega @ V_{GS} = -10V$
- Low gate charge ( typical 6.0 nC)
- Low Crss ( typical 7.5 pF)
- Fast switching
- 100% avalanche tested
- Improved dv/dt capability



#### Absolute Maximum Ratings $T_C = 25^\circ\text{C}$ unless otherwise noted

| Symbol         | Parameter   | FQB3P20 / FQI3P20 | Units               |
|----------------|---|-------------------|---------------------|
| $V_{DSS}$      | Drain-Source Voltage  | -200              | V                   |
| $I_D$          | Drain Current - Continuous ( $T_C = 25^\circ\text{C}$ )                       | -2.8              | A                   |
|                | - Continuous ( $T_C = 100^\circ\text{C}$ )                                    | -1.77             | A                   |
| $I_{DM}$       | Drain Current - Pulsed (Note 1)   | -11.2             | A                   |
| $V_{GSS}$      | Gate-Source Voltage   | $\pm 30$          | V                   |
| $E_{AS}$       | Single Pulsed Avalanche Energy (Note 2)                                       | 150               | mJ                  |
| $I_{AR}$       | Avalanche Current (Note 1)  | -2.8              | A                   |
| $E_{AR}$       | Repetitive Avalanche Energy (Note 1)  | 5.2               | mJ                  |
| dv/dt          | Peak Diode Recovery dv/dt (Note 3)  | -5.5              | V/ns                |
| $P_D$          | Power Dissipation ( $T_A = 25^\circ\text{C}$ ) *                              | 3.13              | W                   |
|                | Power Dissipation ( $T_C = 25^\circ\text{C}$ )                                | 52                | W                   |
|                | - Derate above $25^\circ\text{C}$   | 0.42              | W/ $^\circ\text{C}$ |
| $T_J, T_{STG}$ | Operating and Storage Temperature Range                                       | -55 to +150       | $^\circ\text{C}$    |
| $T_L$          | Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds | 300               | $^\circ\text{C}$    |

#### Thermal Characteristics

| Symbol          | Parameter                                 | Typ | Max  | Units                     |
|-----------------|---|-----|------|---------------------------|
| $R_{\theta JC}$ | Thermal Resistance, Junction-to-Case      | --  | 2.4  | $^\circ\text{C}/\text{W}$ |
| $R_{\theta JA}$ | Thermal Resistance, Junction-to-Ambient * | --  | 40   | $^\circ\text{C}/\text{W}$ |
| $R_{\theta JA}$ | Thermal Resistance, Junction-to-Ambient   | --  | 62.5 | $^\circ\text{C}/\text{W}$ |

\* When mounted on the minimum pad size recommended (PCB Mount)

## Electrical Characteristics

$T_C = 25^\circ\text{C}$  unless otherwise noted

| Symbol                               | Parameter                                 | Test Conditions  | Min  | Typ   | Max  | Units                     |
|--------------------------------------|---|--|------|-------|------|---------------------------|
| <b>Off Characteristics</b>           |   |  |      |       |      |                           |
| $BV_{DSS}$                           | Drain-Source Breakdown Voltage            | $V_{GS} = 0\text{ V}, I_D = -250\ \mu\text{A}$               | -200 | --    | --   | V                         |
| $\frac{\Delta BV_{DSS}}{\Delta T_J}$ | Breakdown Voltage Temperature Coefficient | $I_D = -250\ \mu\text{A}$ , Referenced to $25^\circ\text{C}$ | --   | -0.18 | --   | $\text{V}/^\circ\text{C}$ |
| $I_{DSS}$                            | Zero Gate Voltage Drain Current           | $V_{DS} = -200\text{ V}, V_{GS} = 0\text{ V}$                | --   | --    | -1   | $\mu\text{A}$             |
|                                      |   | $V_{DS} = -160\text{ V}, T_C = 125^\circ\text{C}$            | --   | --    | -10  | $\mu\text{A}$             |
| $I_{GSSF}$                           | Gate-Body Leakage Current, Forward        | $V_{GS} = -30\text{ V}, V_{DS} = 0\text{ V}$                 | --   | --    | -100 | nA                        |
| $I_{GSSR}$                           | Gate-Body Leakage Current, Reverse        | $V_{GS} = 30\text{ V}, V_{DS} = 0\text{ V}$                  | --   | --    | 100  | nA                        |

## On Characteristics

|              |                                   |   |      |      |      |          |
|--------------|-----------------------------------|---|------|------|------|----------|
| $V_{GS(th)}$ | Gate Threshold Voltage            | $V_{DS} = V_{GS}, I_D = -250\ \mu\text{A}$            | -3.0 | --   | -5.0 | V        |
| $R_{DS(on)}$ | Static Drain-Source On-Resistance | $V_{GS} = -10\text{ V}, I_D = -1.4\text{ A}$          | --   | 2.06 | 2.7  | $\Omega$ |
| $g_{FS}$     | Forward Transconductance          | $V_{DS} = -40\text{ V}, I_D = -1.4\text{ A}$ (Note 4) | --   | 1.23 | --   | S        |

## Dynamic Characteristics

|           |                              |   |    |     |     |    |
|-----------|------------------------------|---|----|-----|-----|----|
| $C_{iss}$ | Input Capacitance            | $V_{DS} = -25\text{ V}, V_{GS} = 0\text{ V},$<br>$f = 1.0\text{ MHz}$ | -- | 190 | 250 | pF |
| $C_{oss}$ | Output Capacitance           |   | -- | 45  | 60  | pF |
| $C_{rss}$ | Reverse Transfer Capacitance |   | -- | 7.5 | 10  | pF |

## Switching Characteristics

|              |                     |   |             |     |     |    |    |
|--------------|---------------------|---|-------------|-----|-----|----|----|
| $t_{d(on)}$  | Turn-On Delay Time  | $V_{DD} = -100\text{ V}, I_D = -2.8\text{ A},$<br>$R_G = 25\ \Omega$      | --          | 8.5 | 25  | ns |    |
| $t_r$        | Turn-On Rise Time   |   | --          | 35  | 80  | ns |    |
| $t_{d(off)}$ | Turn-Off Delay Time |   | (Note 4, 5) | --  | 12  | 35 | ns |
| $t_f$        | Turn-Off Fall Time  |   | (Note 4, 5) | --  | 25  | 60 | ns |
| $Q_g$        | Total Gate Charge   | $V_{DS} = -160\text{ V}, I_D = -2.8\text{ A},$<br>$V_{GS} = -10\text{ V}$ | --          | 6.0 | 8.0 | nC |    |
| $Q_{gs}$     | Gate-Source Charge  |   | (Note 4, 5) | --  | 1.7 | -- | nC |
| $Q_{gd}$     | Gate-Drain Charge   |   | (Note 4, 5) | --  | 2.9 | -- | nC |

## Drain-Source Diode Characteristics and Maximum Ratings

|          |   |  |    |       |      |               |
|----------|---|--|----|-------|------|---------------|
| $I_S$    | Maximum Continuous Drain-Source Diode Forward Current | --   | -- | -2.8  | A    |               |
| $I_{SM}$ | Maximum Pulsed Drain-Source Diode Forward Current     | --   | -- | -11.2 | A    |               |
| $V_{SD}$ | Drain-Source Diode Forward Voltage                    | $V_{GS} = 0\text{ V}, I_S = -2.8\text{ A}$   | -- | --    | -5.0 | V             |
| $t_{rr}$ | Reverse Recovery Time                                 | $V_{GS} = 0\text{ V}, I_S = -2.8\text{ A},$<br>$dI_F / dt = 100\text{ A}/\mu\text{s}$ (Note 4) | -- | 100   | --   | ns            |
| $Q_{rr}$ | Reverse Recovery Charge                               |  | -- | 0.34  | --   | $\mu\text{C}$ |

### Notes:

1. Repetitive Rating : Pulse width limited by maximum junction temperature
2.  $L = 29\text{mH}, I_{AS} = -2.8\text{ A}, V_{DD} = -50\text{ V}, R_G = 25\ \Omega$ , Starting  $T_J = 25^\circ\text{C}$
3.  $I_{SD} \leq -2.8\text{ A}, dI/dt \leq 300\text{ A}/\mu\text{s}, V_{DD} \leq BV_{DSS}$ , Starting  $T_J = 25^\circ\text{C}$
4. Pulse Test : Pulse width  $\leq 300\ \mu\text{s}$ , Duty cycle  $\leq 2\%$
5. Essentially independent of operating temperature

## Typical Characteristics

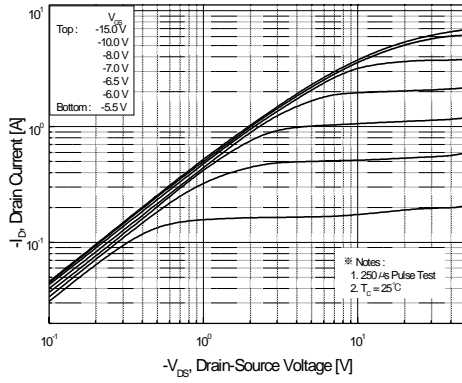


Figure 1. On-Region Characteristics

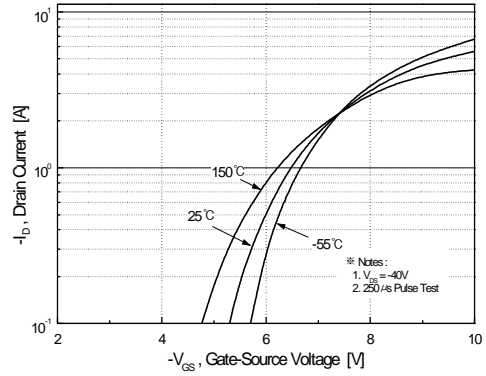


Figure 2. Transfer Characteristics

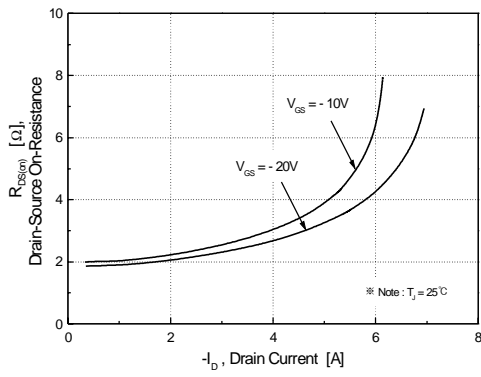


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

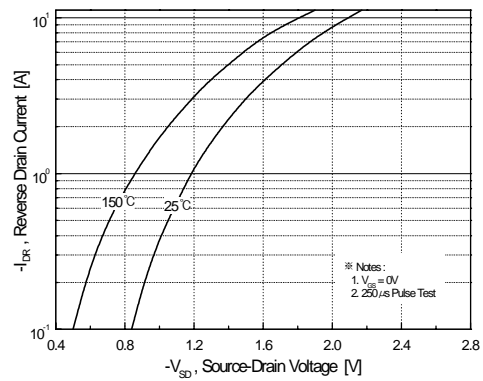


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

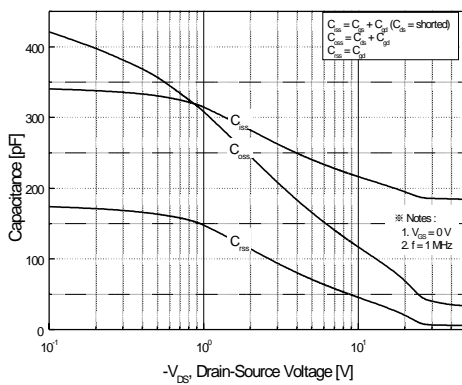


Figure 5. Capacitance Characteristics

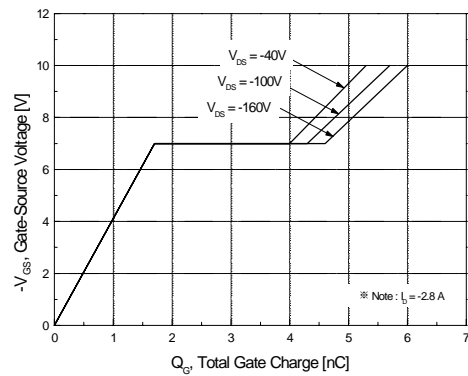
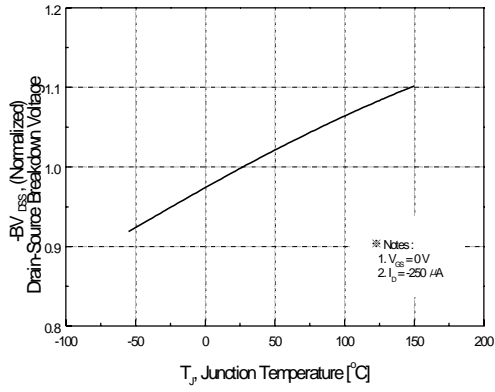
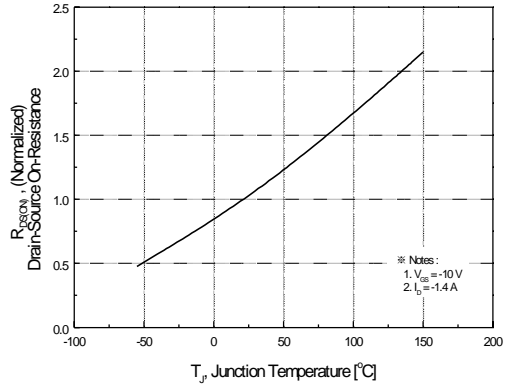


Figure 6. Gate Charge Characteristics

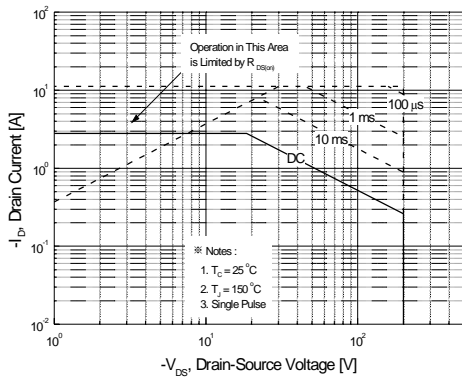
**Typical Characteristics** (Continued)



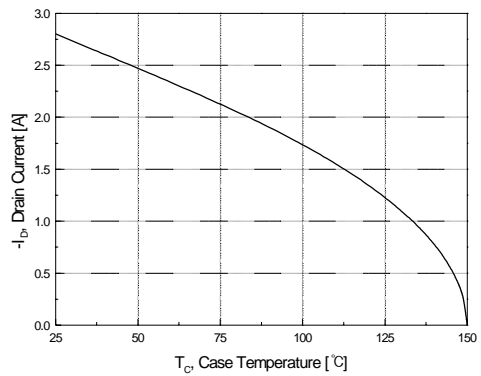
**Figure 7. Breakdown Voltage Variation vs. Temperature**



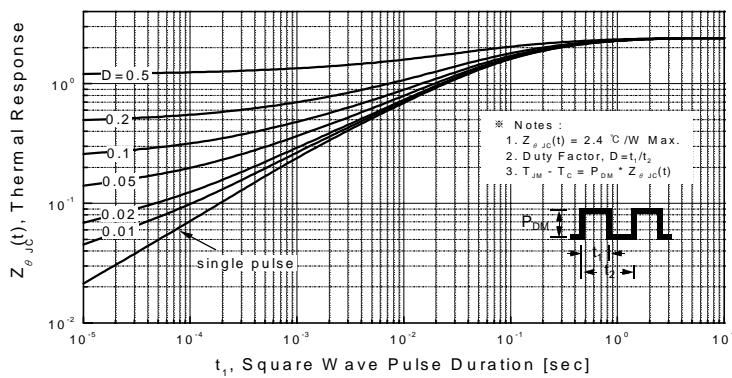
**Figure 8. On-Resistance Variation vs. Temperature**



**Figure 9. Maximum Safe Operating Area**

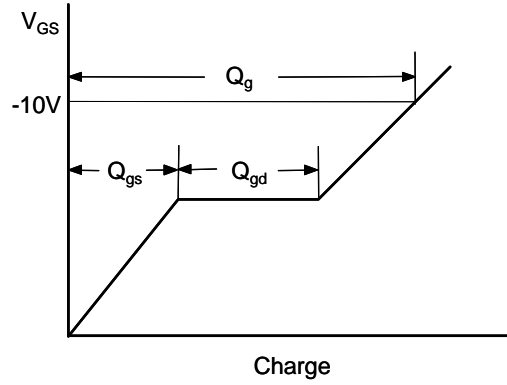
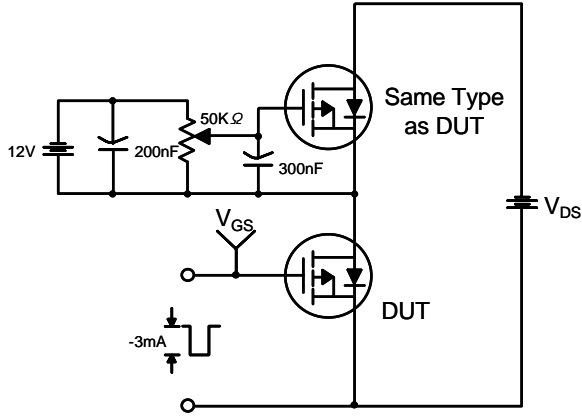


**Figure 10. Maximum Drain Current vs. Case Temperature**

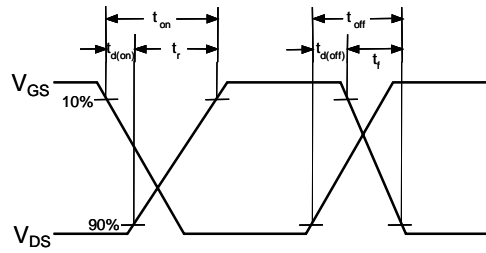
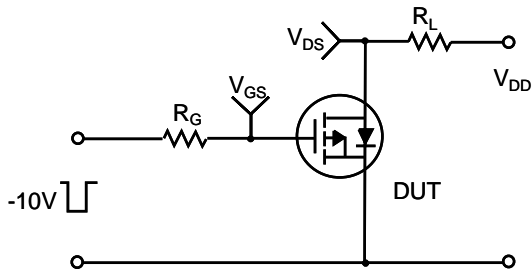


**Figure 11. Transient Thermal Response Curve**

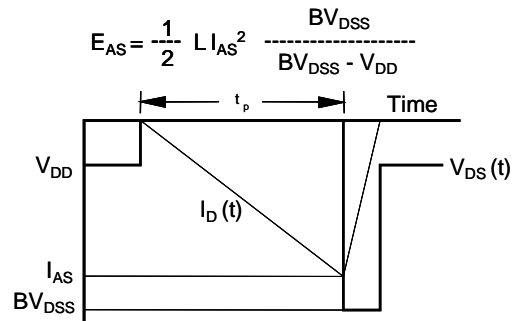
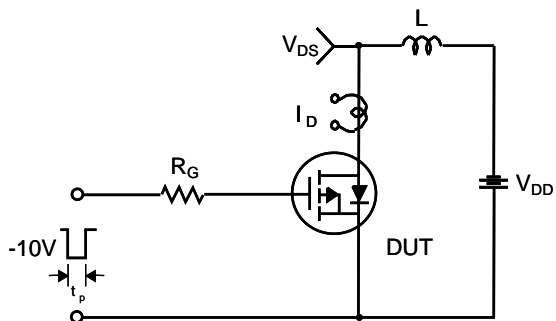
Gate Charge Test Circuit & Waveform



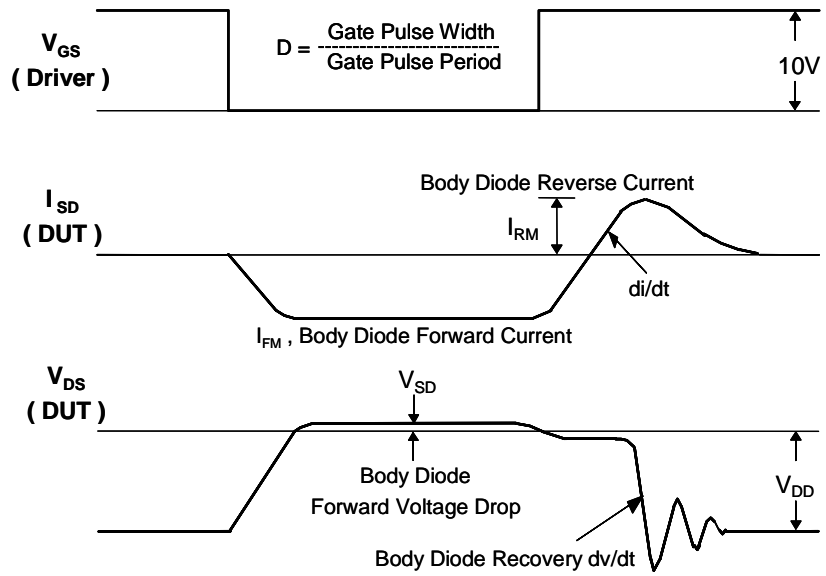
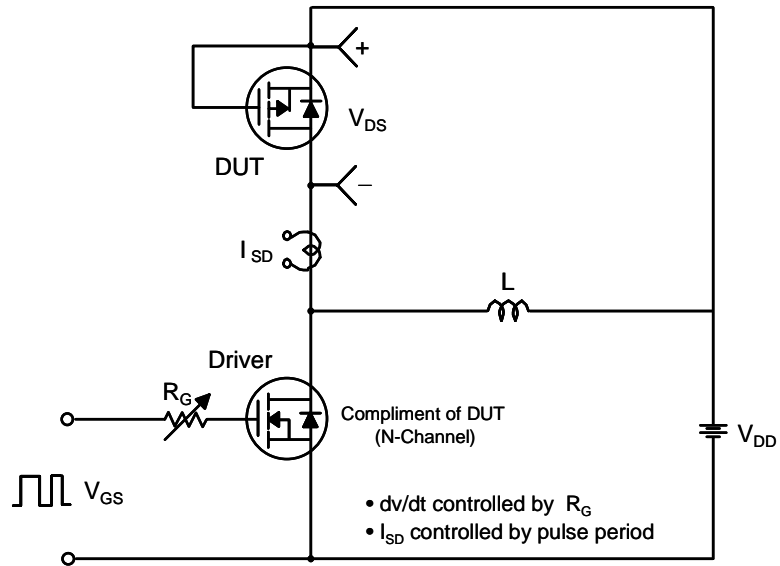
Resistive Switching Test Circuit & Waveforms



Unclamped Inductive Switching Test Circuit & Waveforms

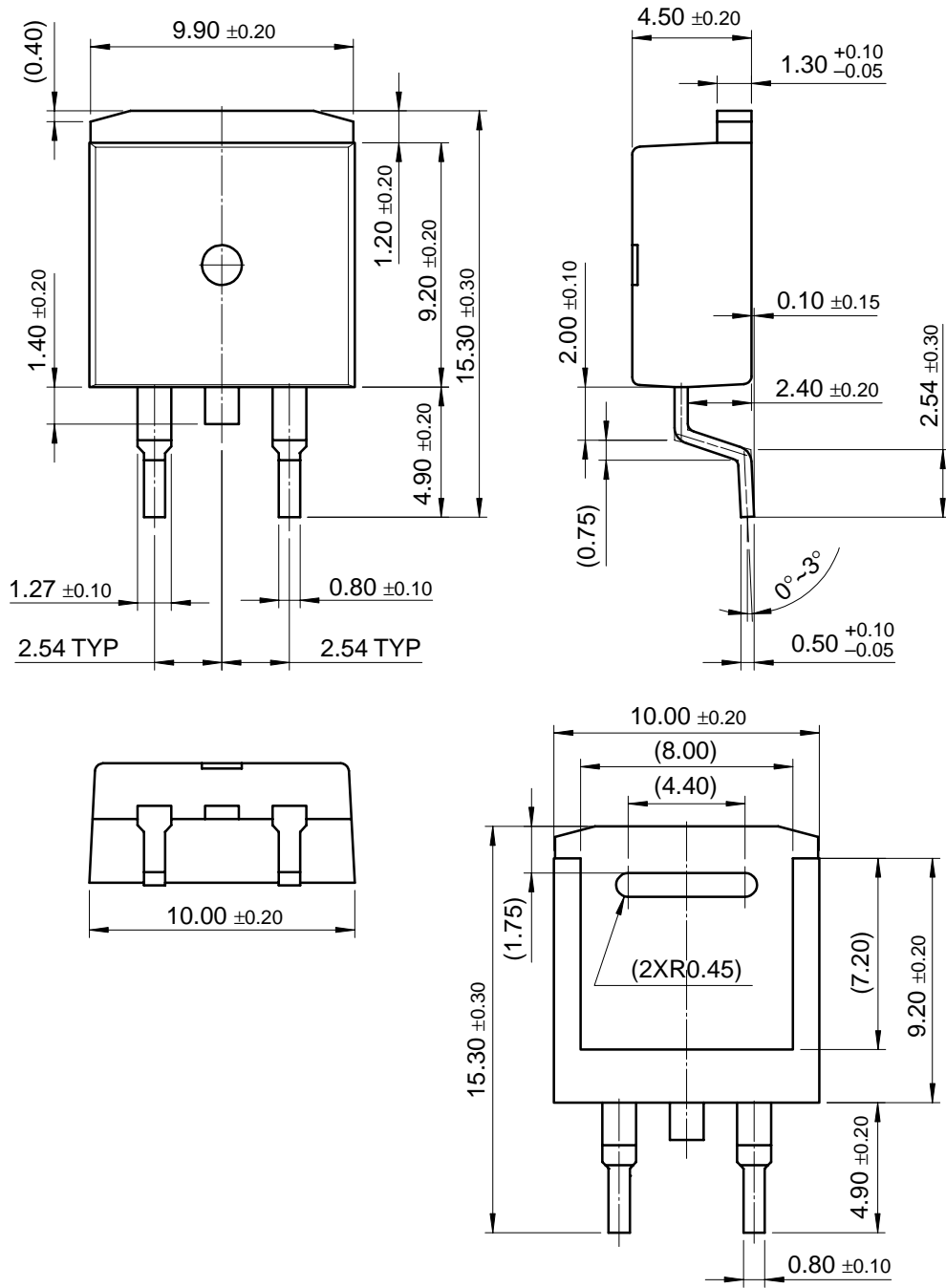


Peak Diode Recovery dv/dt Test Circuit & Waveforms



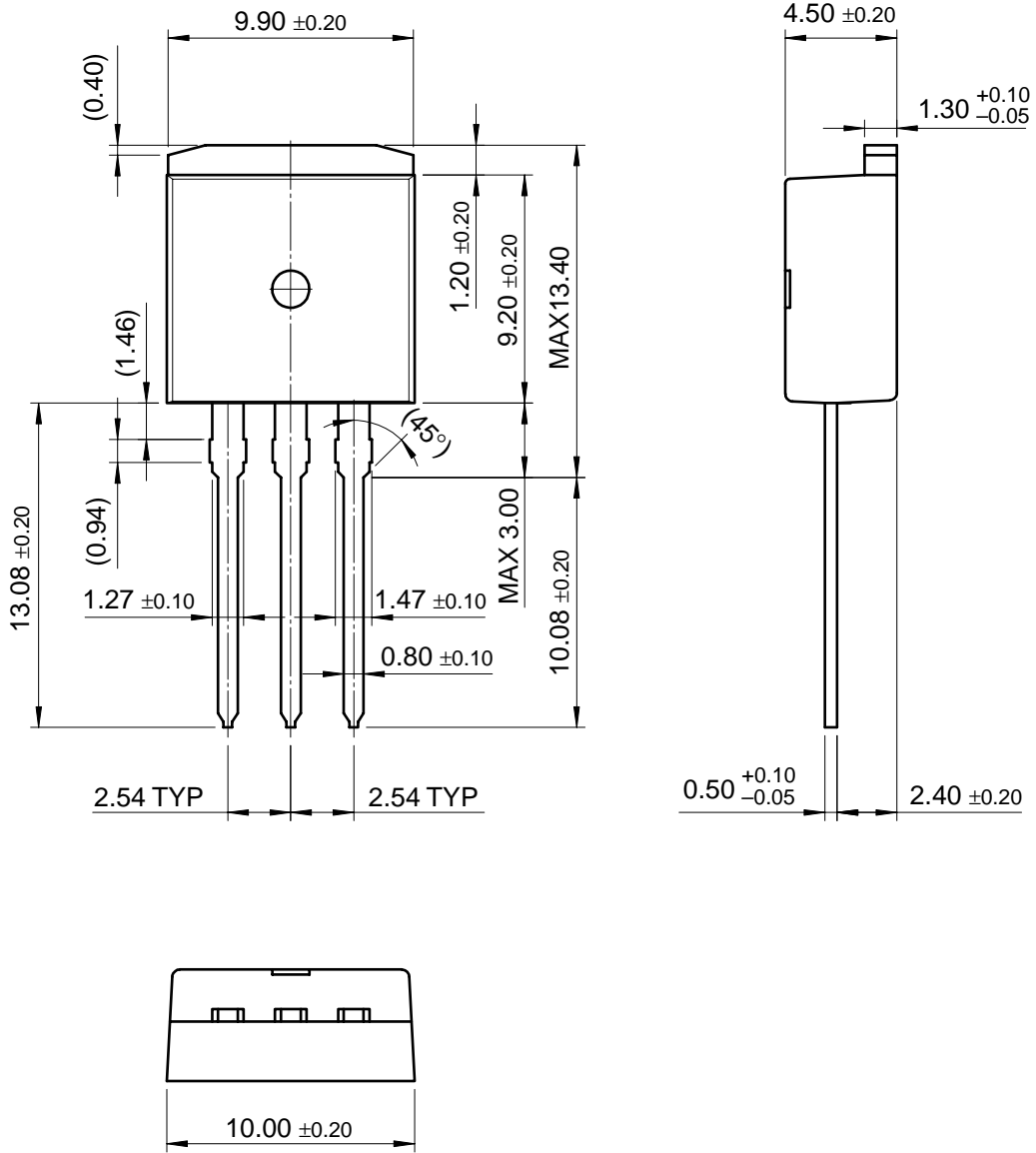
Package Dimensions

D<sup>2</sup>PAK



Package Dimensions (Continued)

# I<sup>2</sup>PAK



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